

# **Coupling of Electromagnetic Fields to Circuits in a Cavity**

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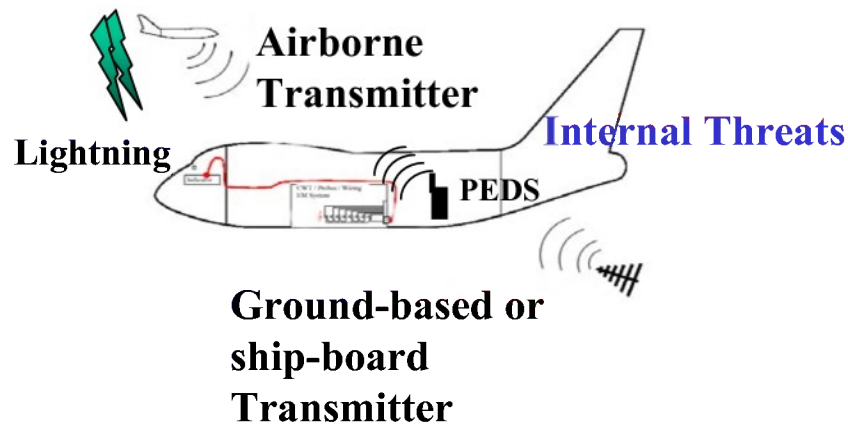
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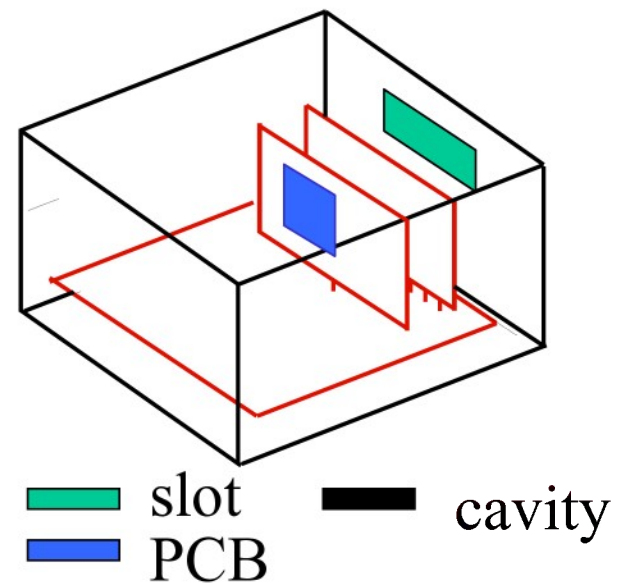
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# As Part of Our MURI Effort, We Are to Develop Capabilities for Modeling Complex EMC/EMI Problems

## External Threats



(Picture from NASA-Langley)

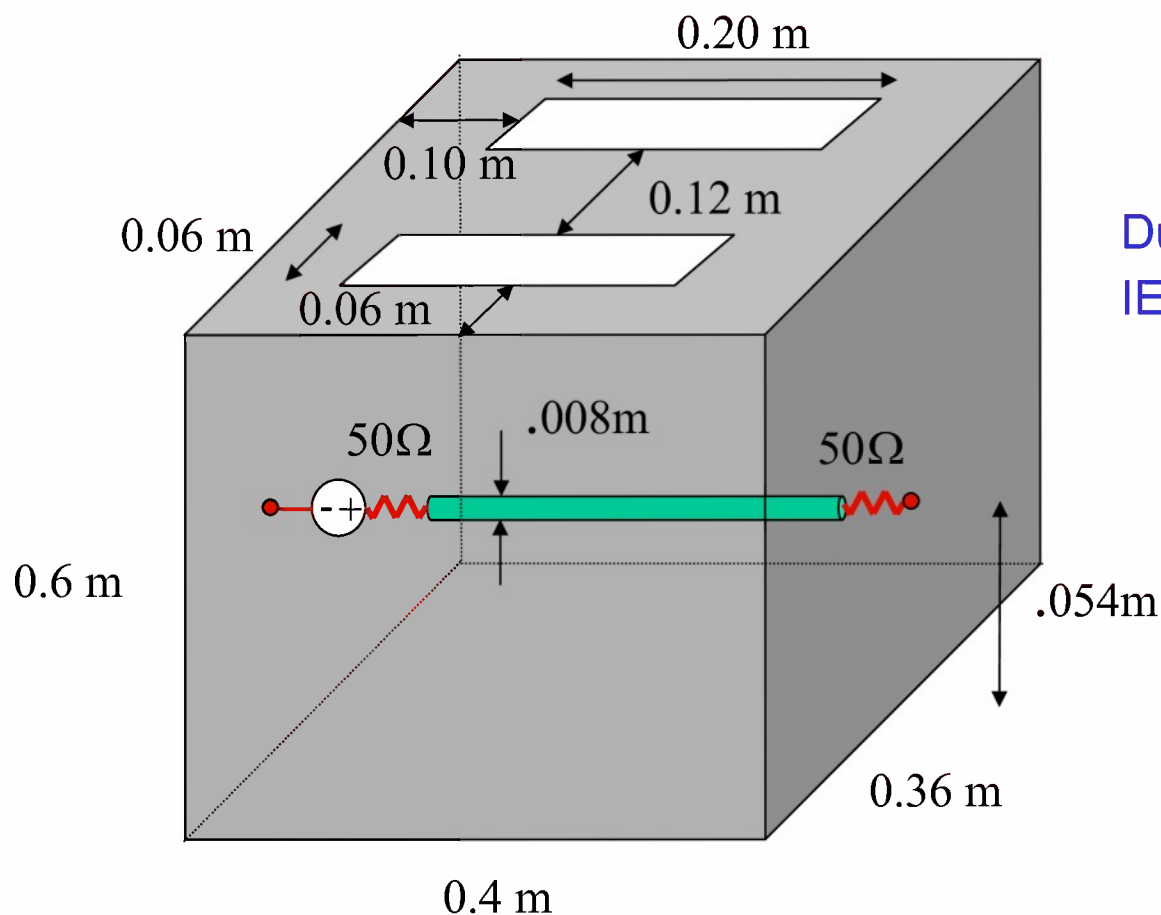


## **As a First Step, We Want to Determine EIGER's Suitability for Code Validation and for Performing General-Purpose EMC/EMI Calculations**

- **EIGER is a general-purpose EM frequency domain modeling code being jointly developed by**
  - **U. Houston/NASA**
  - **Navy (SPAWAR)**
  - **Lawrence Livermore National Laboratory**
  - **Sandia National Laboratories**
- **Can EIGER be used to obtain quick results and handle difficult-to-formulate EMC/EMI calculations?**
- **Can EIGER be used to validate new codes, and to efficiently obtain desired model parameters?**
- **Can it be used as a breadboard for developing more specialized codes?**

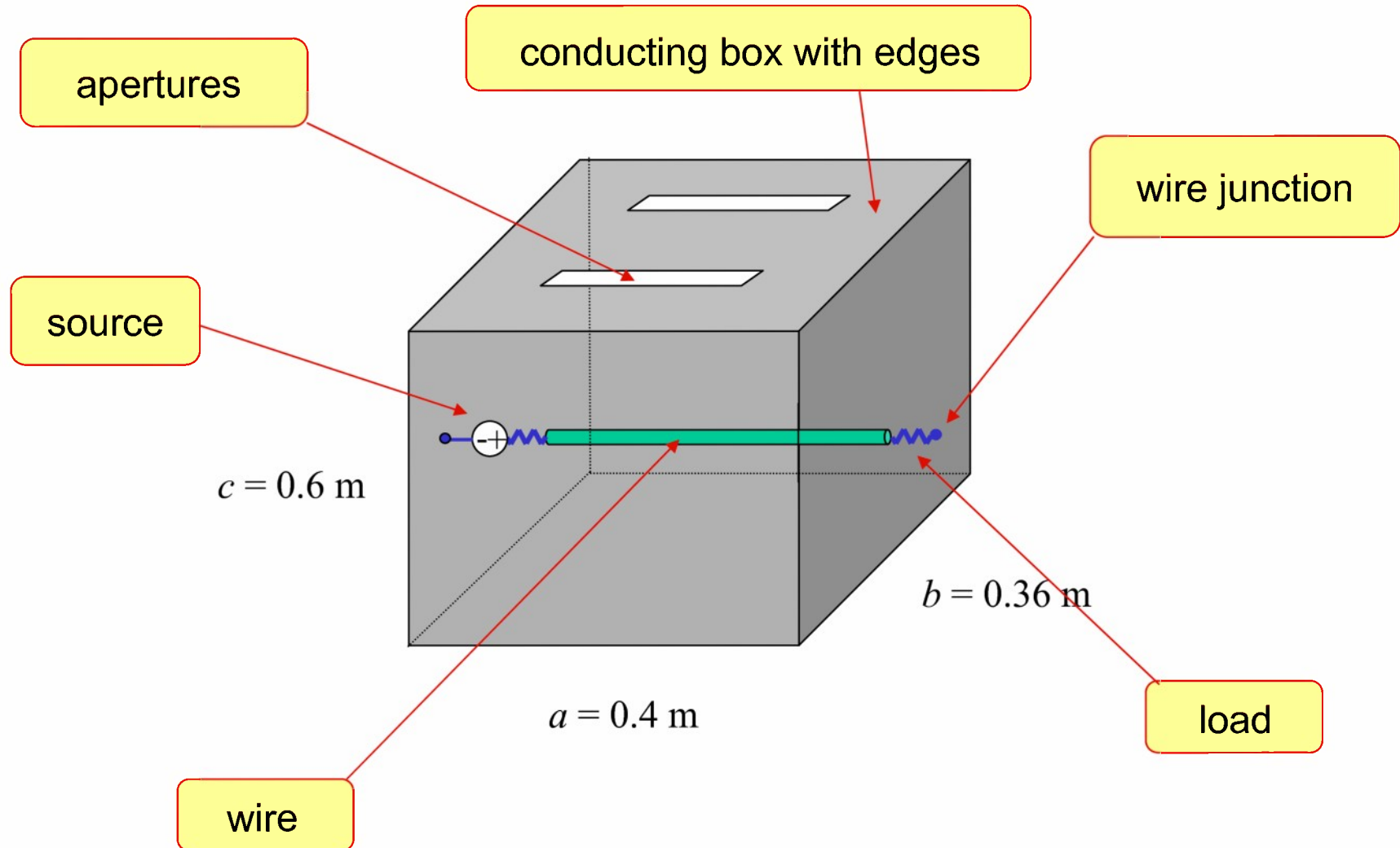
## Validation Study

**A Conducting Box with Two Apertures, Containing a  
Conducting Wire with  $50\ \Omega$  Loads Terminating on Box Walls,  
Excited by a 1-Volt RF Source**



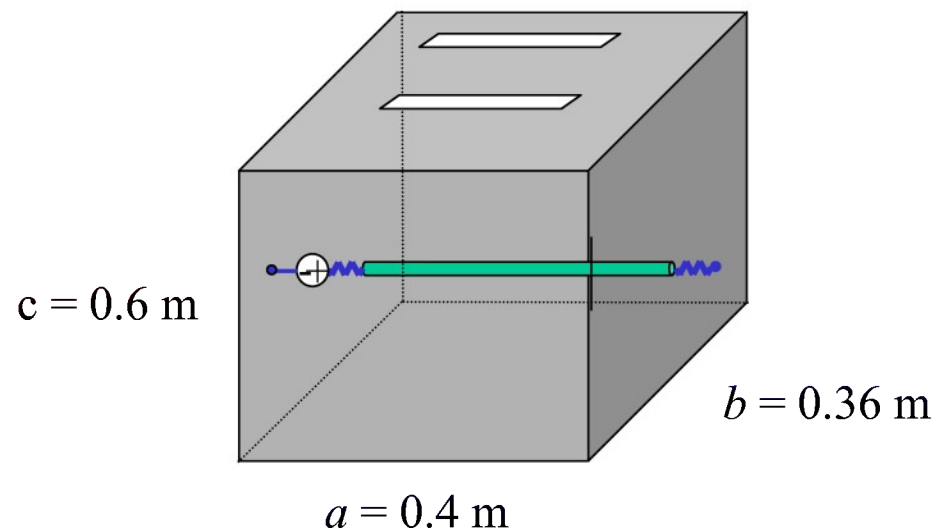
Duffy, Benson, Christopoulos  
IEEE EMC, 36 (2), May '94

# Canonical Problem That Exercises Code Capabilities



# Numerical Validation: Three Approaches

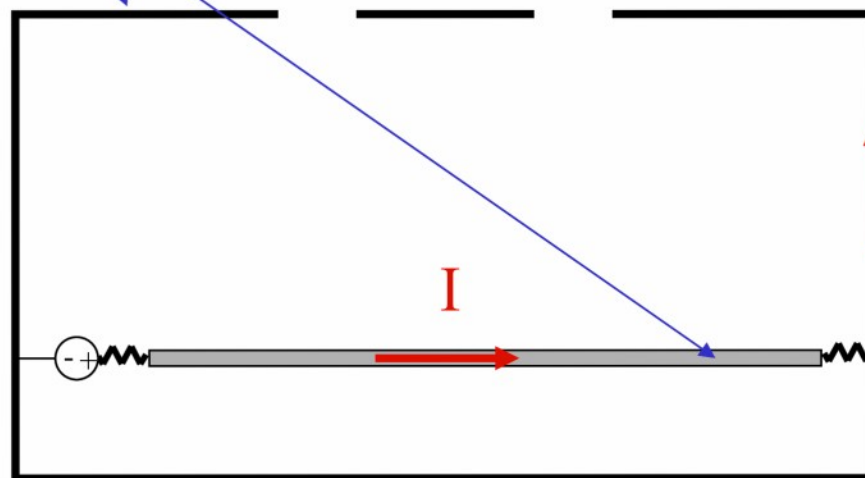
- Direct EFIE approach
- Aperture integral equation with EFIE
- Aperture integral equation with EFIE and cavity Green's function
- These are compared to measurements (EMC paper)



## Approach #1: Direct EFIE

The system is treated as one conducting object  
(with source, loads, and junctions)

$$\hat{n} \times E[J_s, I] = 0$$



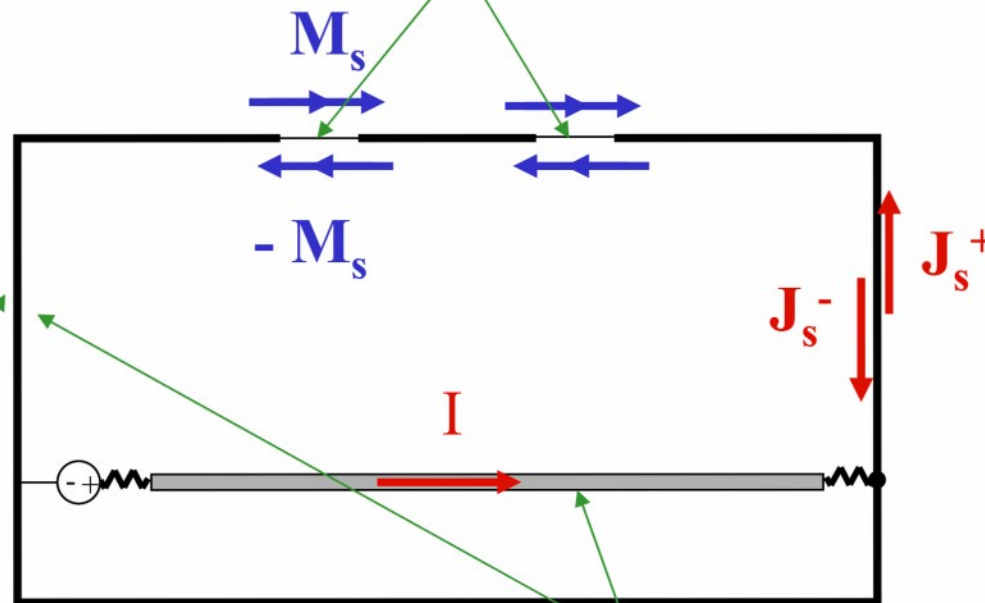
$J_s$  (total current)



## Approach #2: EFIE with AIE

The system is divided into two regions.  
An Aperture Integral Equation (AIE) is enforced.

$$\hat{n} \times H^+ [J_s^+, M_s] = \hat{n} \times H^- [J_s^-, -M_s, I]$$

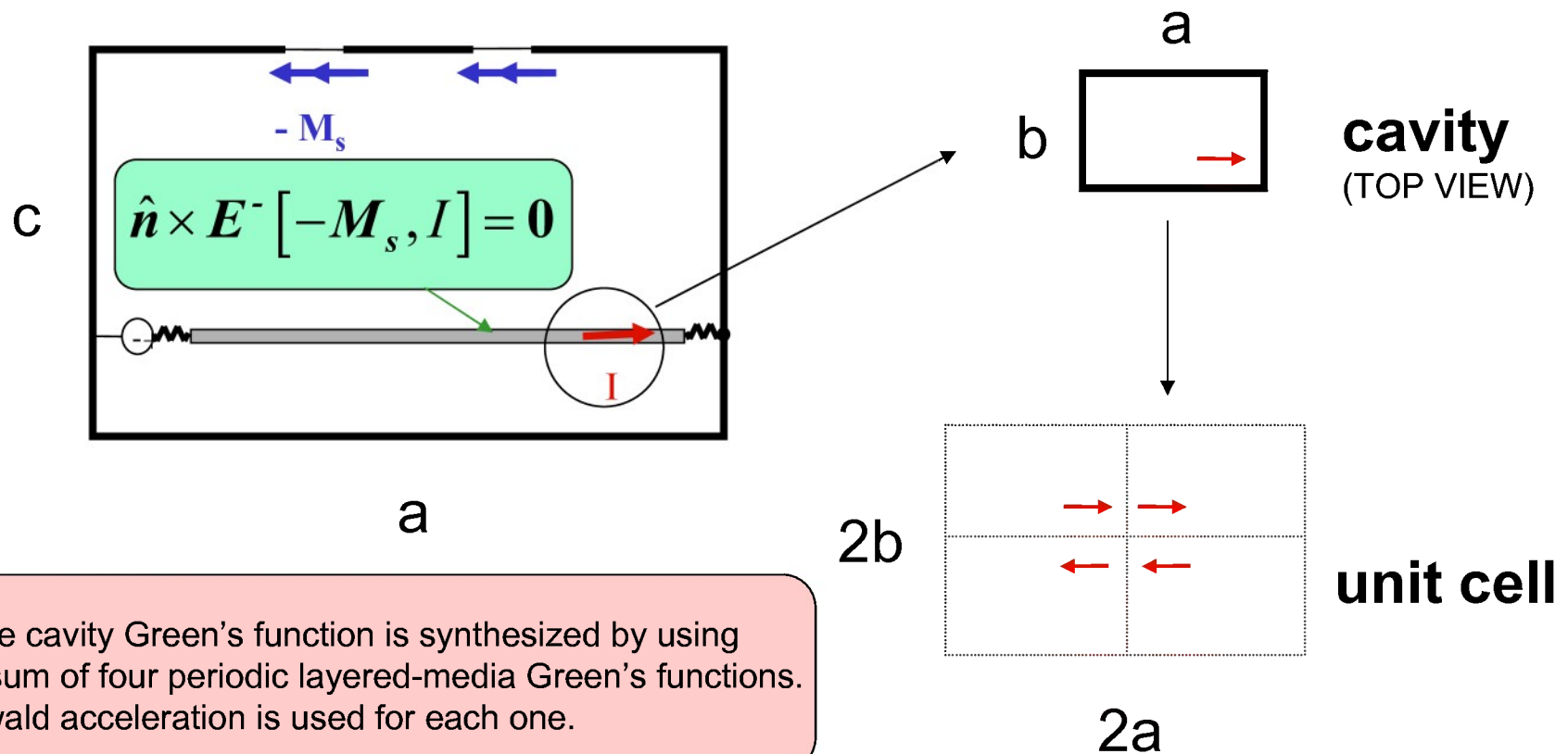


$$\hat{n} \times E^+ [J_s^+, M_s] = 0$$

$$\hat{n} \times E^- [J_s^-, -M_s, I] = 0$$

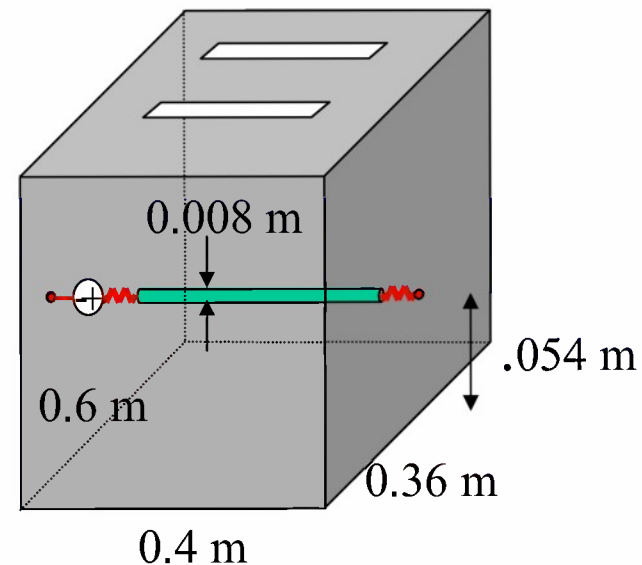
# Approach #3: EFIE with AIE and Cavity Green's Function

An AIE is used as in approach 2. A **cavity Green's function** is used to calculate the interior fields.



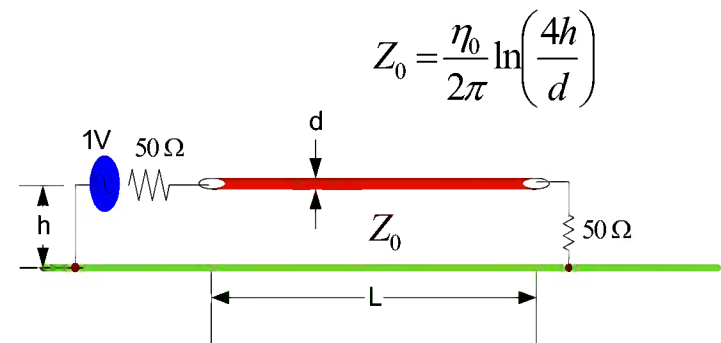
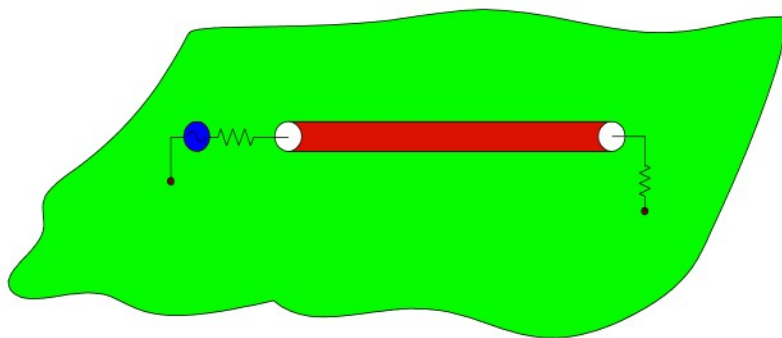
# Results

- Determine normalized output current at opposite end of line excited by a 1 V source
- Compare to measurement (Duffy et al., IEEE Trans. EMC, May 1994, pp. 144 -146)



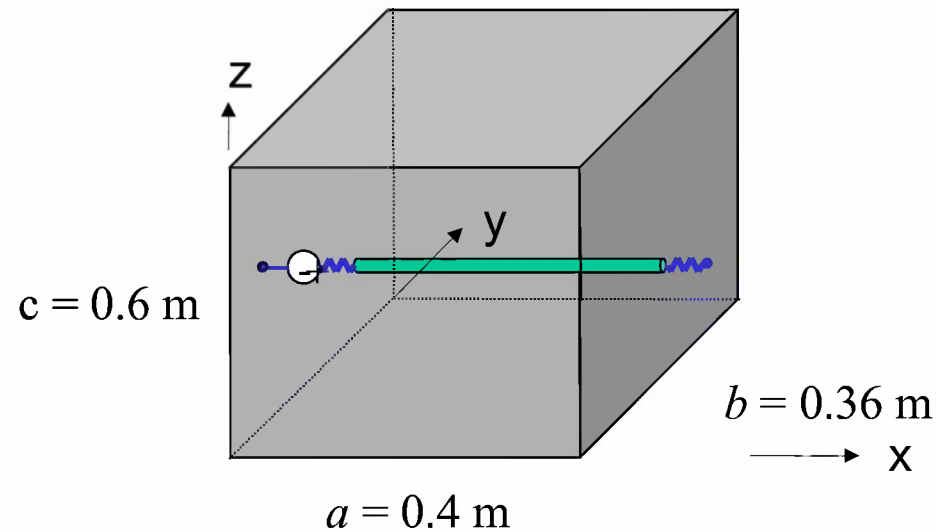
# Compare to Transmission Line Approximation...

Use transmission line theory to approximate the current at the end load.



## ... and Compare Computed vs. Theoretical Cavity Resonances

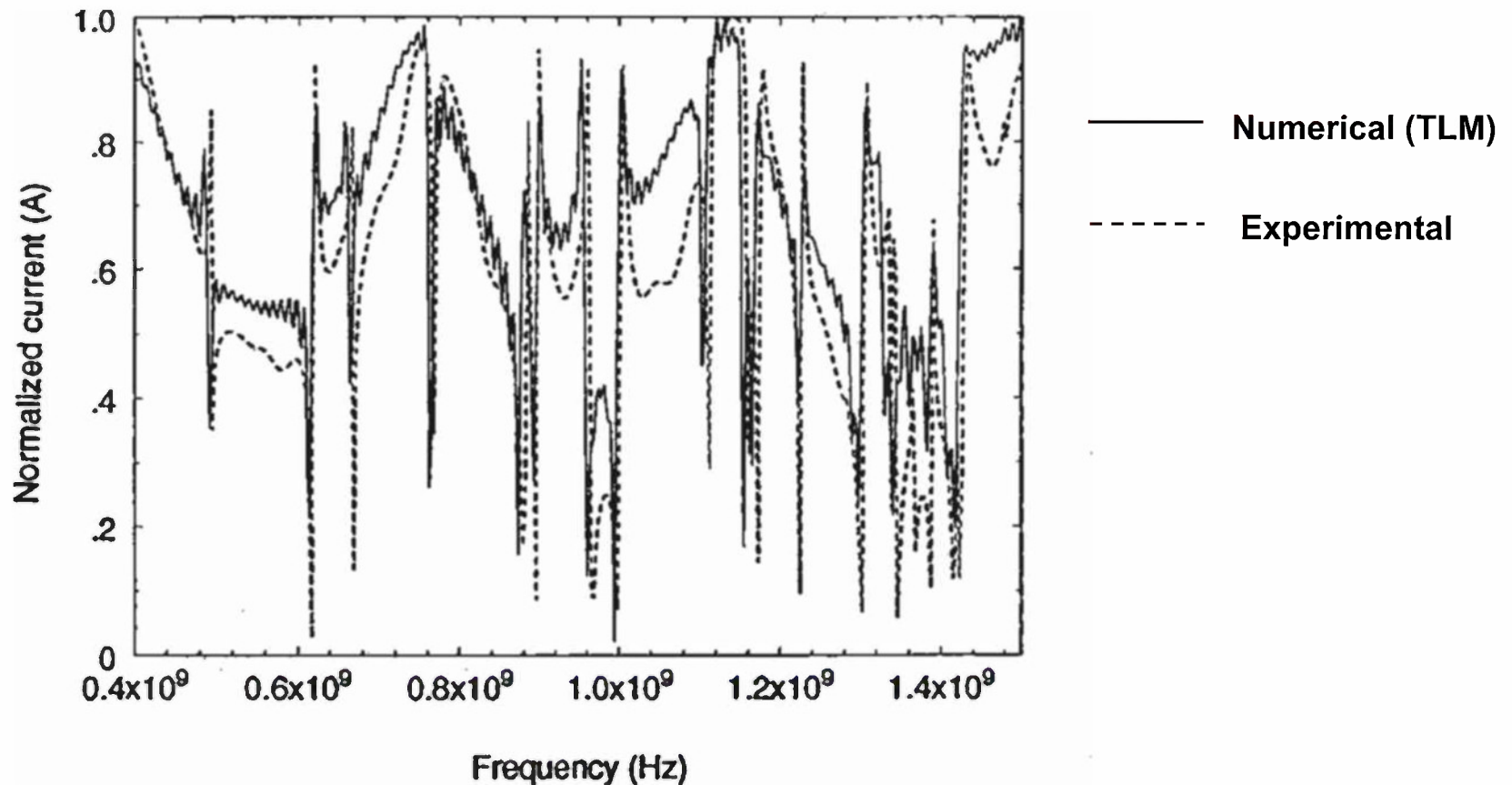
Predict the resonant frequency of the cavity



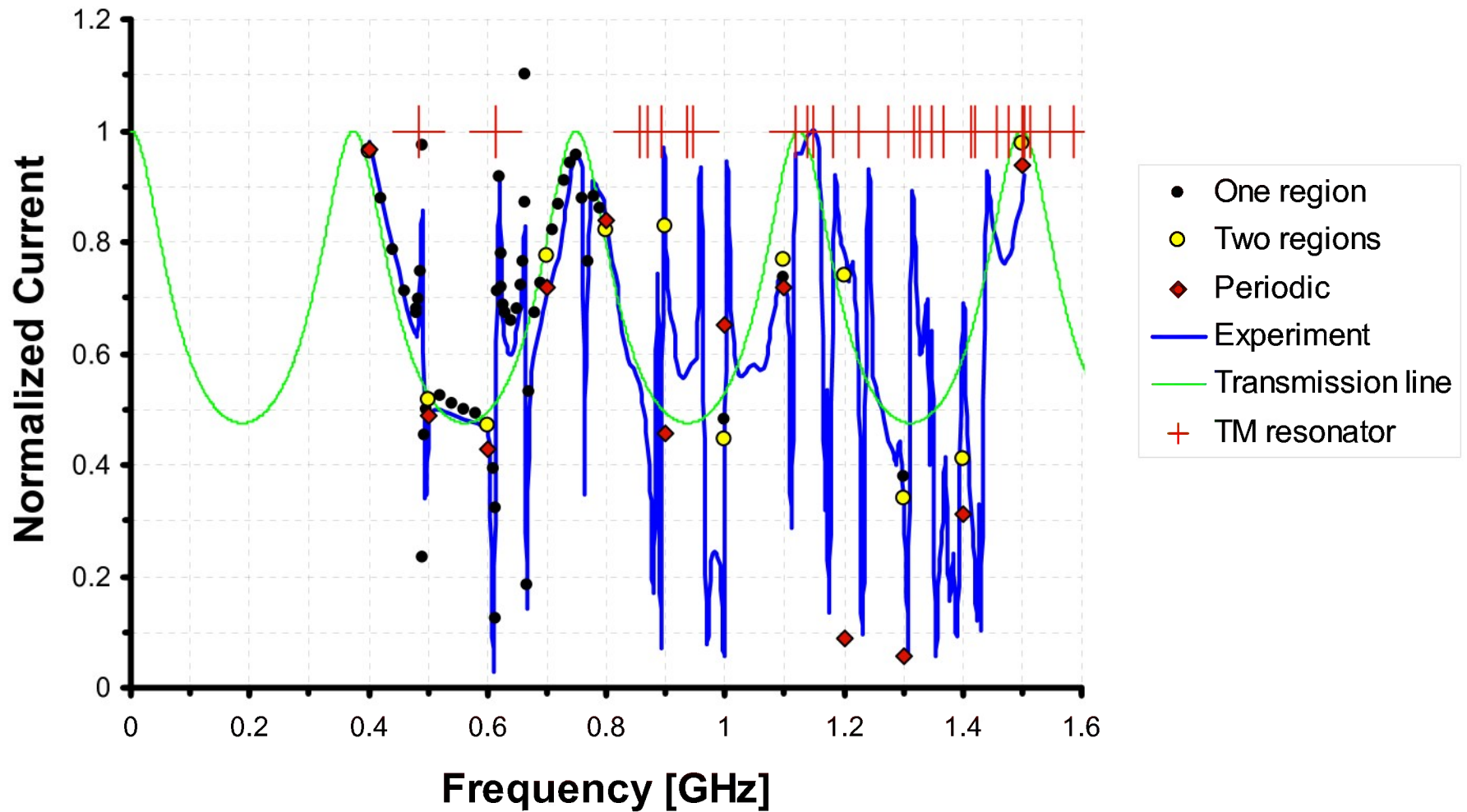
The wire excites  $\text{TM}_{mnp}$  cavity modes  
for  $m = 0, 1, 2, \dots$ ;  $n = 1, 3, 5, \dots$ ;  $p = 1, 2, 3, \dots$

# TML and Experimental Results from Duffy et al.

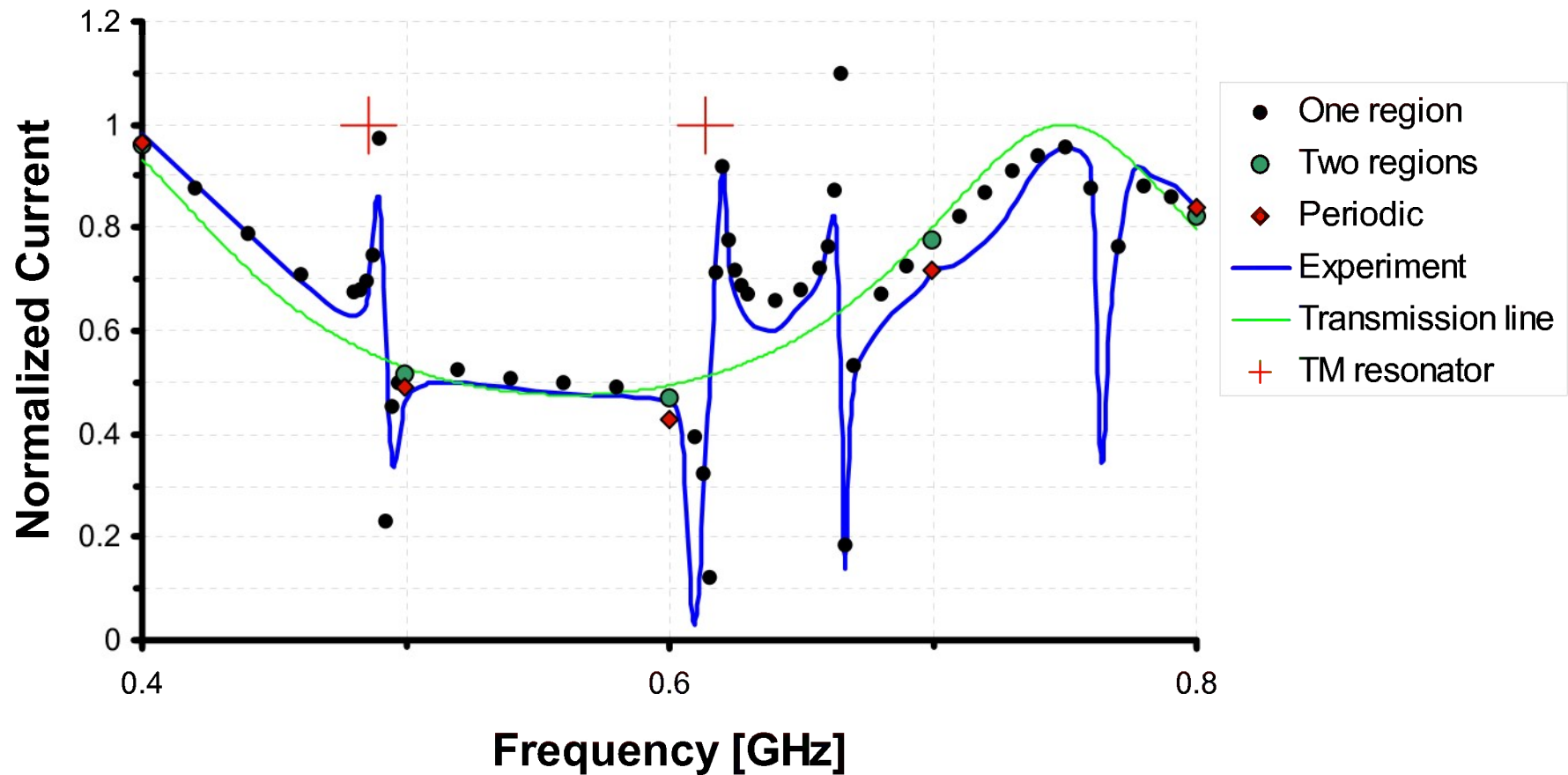
- Fourier transformed TML results
- Both results normalized to peaks



# Normalized Current at the Load Opposite the Source



## Detail of Current Plot (0.4 to 0.8 GHz)





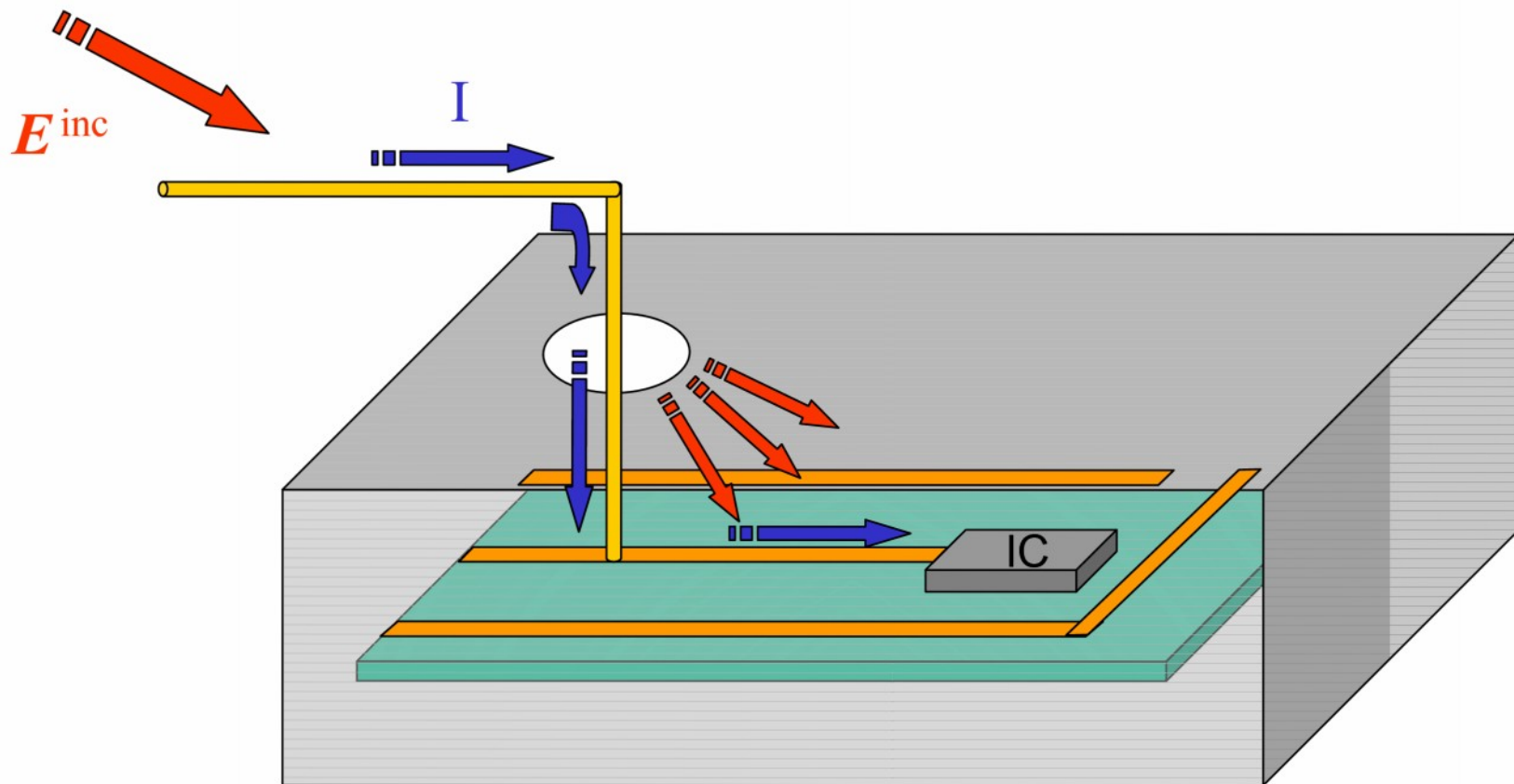
## Summary of EIGER Validation

- Consistent results are obtained utilizing three different formulations for a complex cavity/wire/aperture problem
- Results in agreement with independent experiments and calculations
- EIGER can be useful in EMC/EMI applications both as a stand-alone code and as a code validation tool

# Canonical Problem

## Cable-Through-Aperture Coupling to PCB Traces

This is an important coupling “tube” in the EMC/EMI analysis of digital circuit effects



# Canonical Problem

## Issues, Goals, and Approaches

### Issues:

- ❖ The cavity enclosure must be considered for an accurate solution.
- ❖ The PCB trace may be very complicated, and on a very different size scale than the cavity.

### Goal:

Separate the cavity analysis from the PCB analysis to the maximum extent possible.

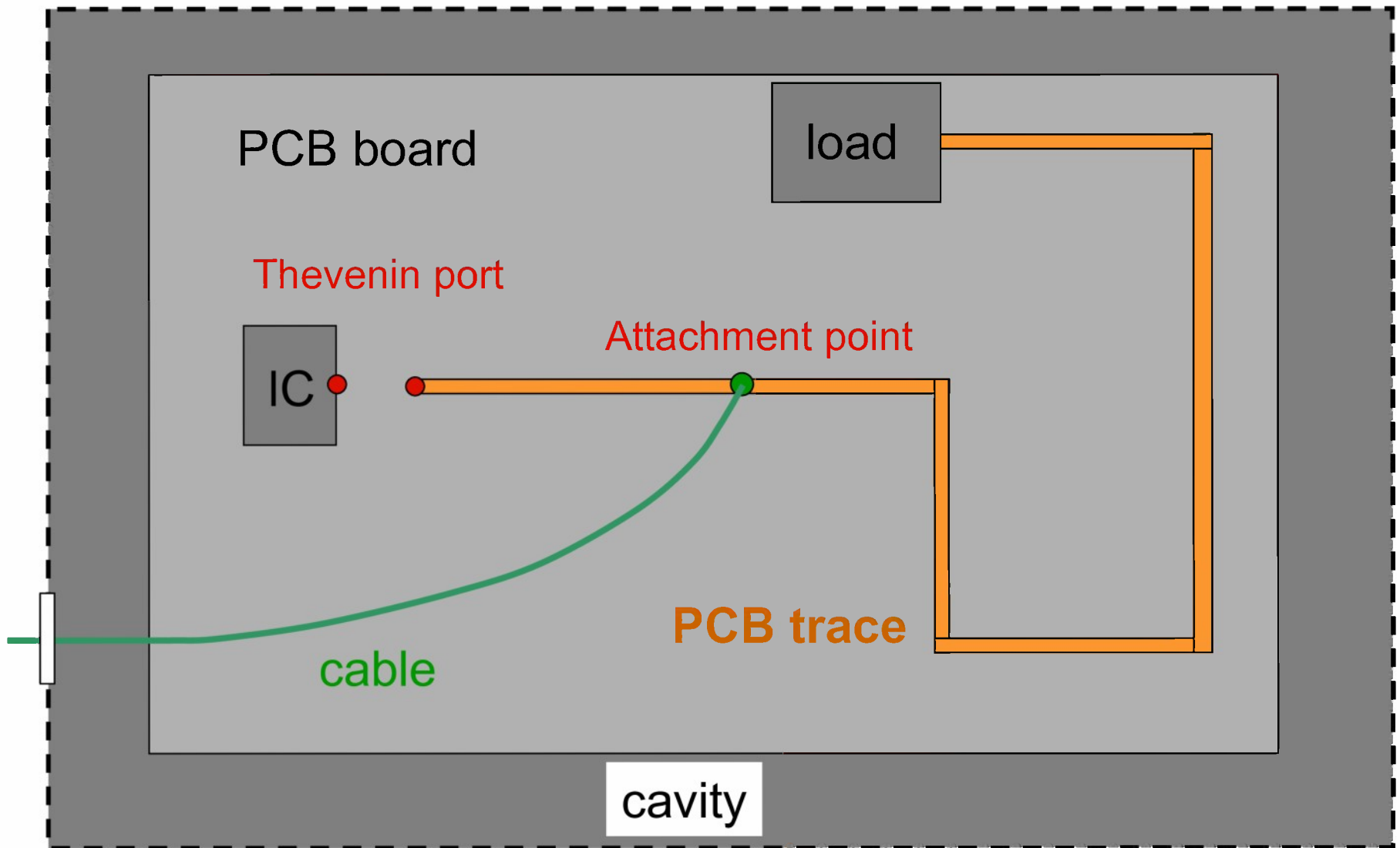
# Approach

- ❖ Calculate a Thévenin equivalent circuit at the input of the digital device (requires  $V^{oc}$  and  $I^{sc}$ ).
- ❖ Use transmission line theory (with distributed sources) to model the PCB trace.
- ❖ Use EIGER to model the cable inside the cavity and the cavity fields, and combine this with the PCB transmission line modeling.

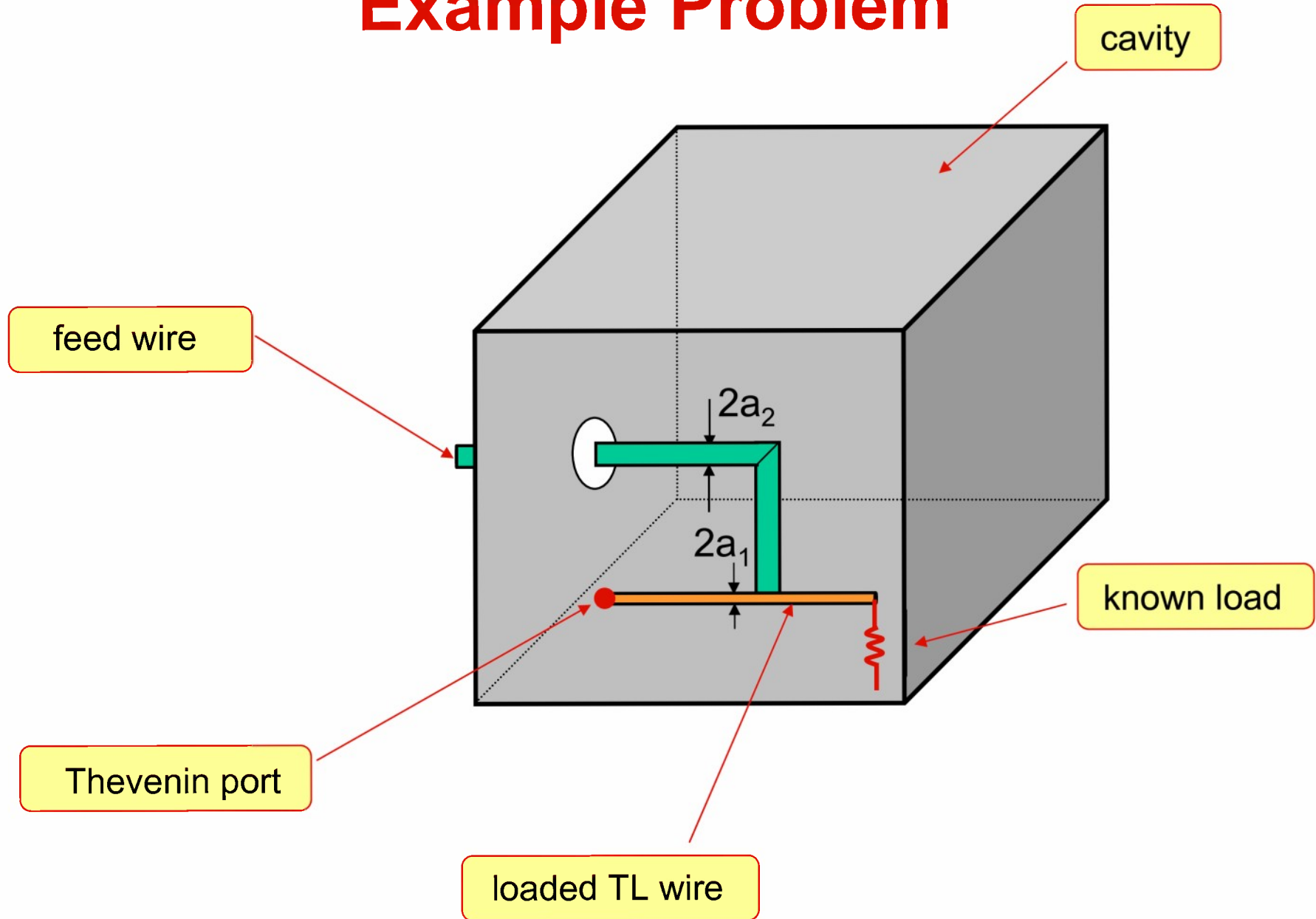


A hybrid method is developed that combines the rigorous cavity-field calculations of EIGER with transmission line theory.

# Top View of Coupling Problem

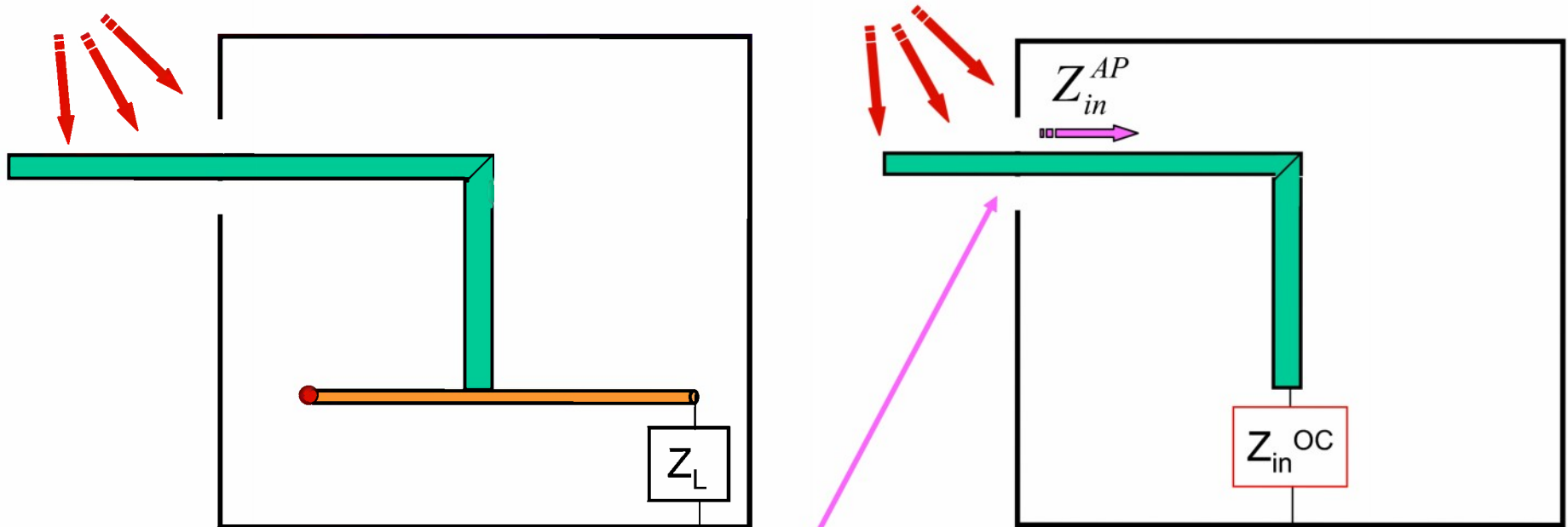


# Example Problem



# Voltage Source Replaces Gap at the Aperture

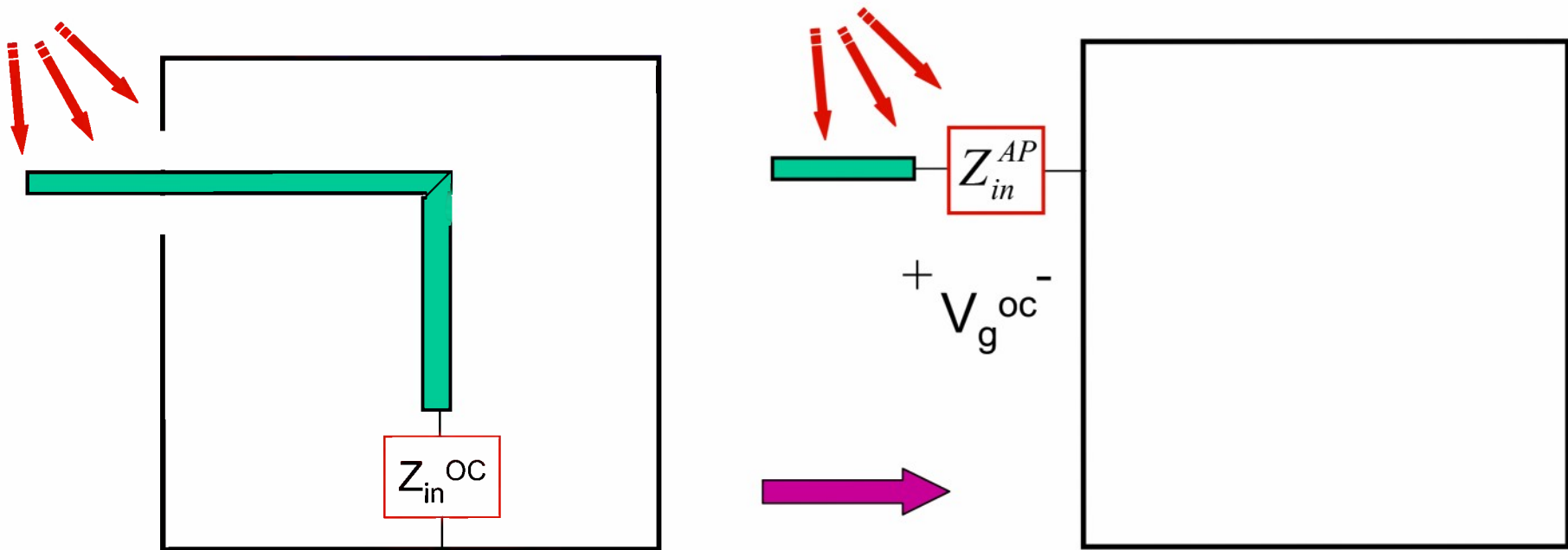
Step 1: PCB trace is replaced by load  $Z_{in}$



$Z_{in}^{AP}$  is the input impedance seen looking into the cavity

# Voltage Source Replaces Gap at the Aperture (cont.)

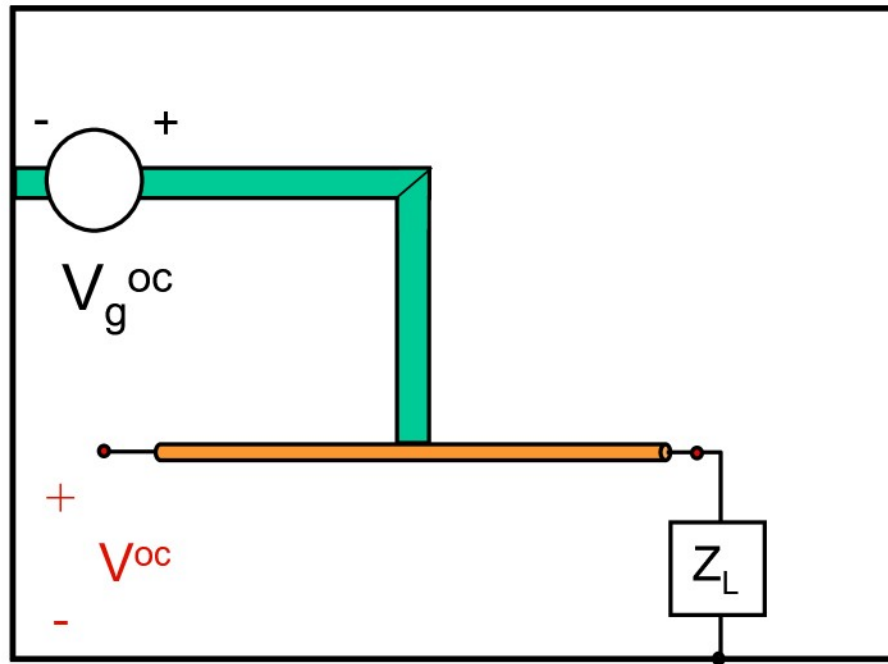
Step 2: internal wire feed is replaced by load



Exterior model for calculation of gap voltage

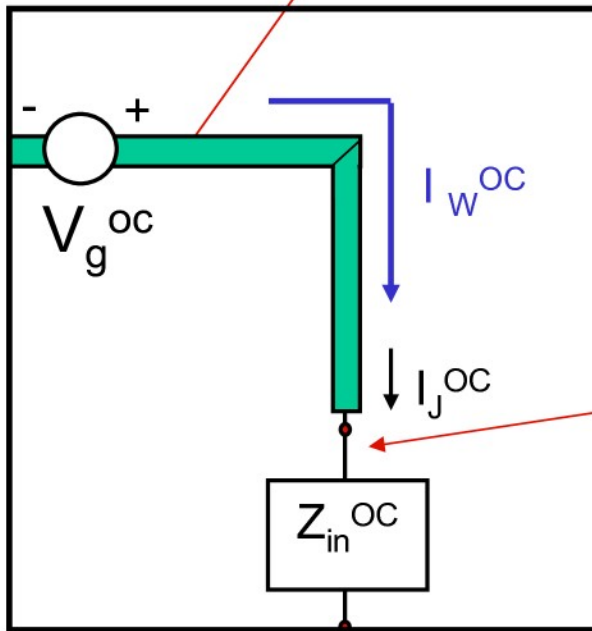


## Voltage Source Replaces Gap at the Aperture (cont.)



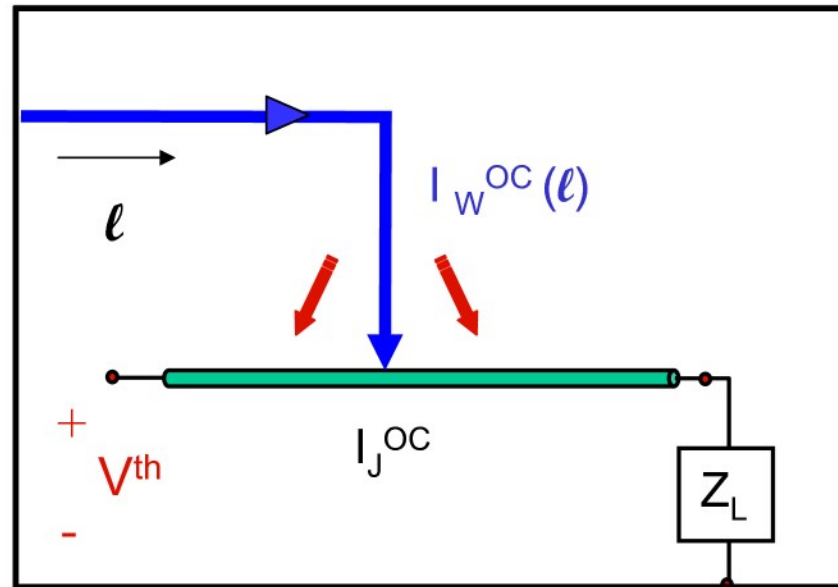
# Current on the Wire is Calculated

The current on the feed wire and at the junction can be calculated by using EIGER.



# Equivalence Principle Is Applied to the Feed Wire

(metal feed wire is removed)



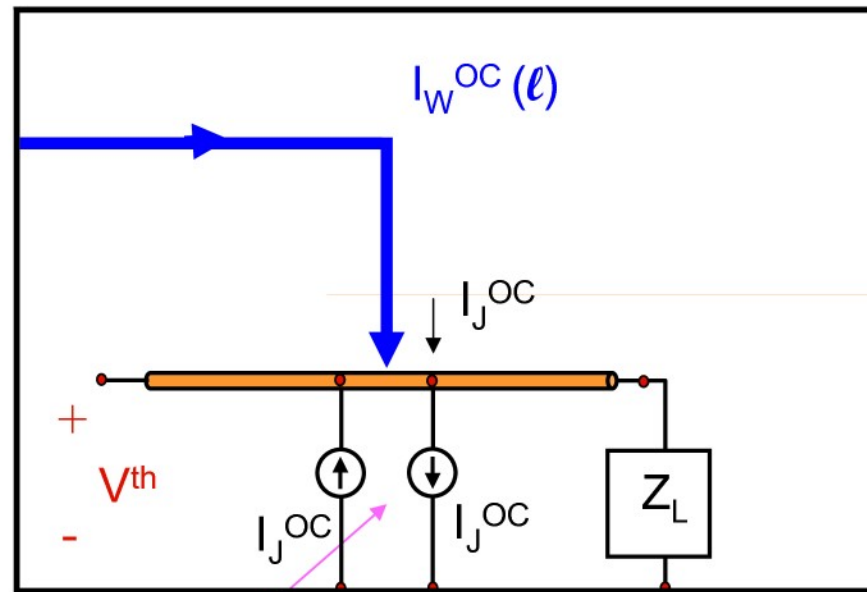
The feed current produces an output voltage in two ways:

- (1) direct current injection
- (2) radiation inside cavity

$$V^{th} = V_I^{th} + V_R^{th}$$

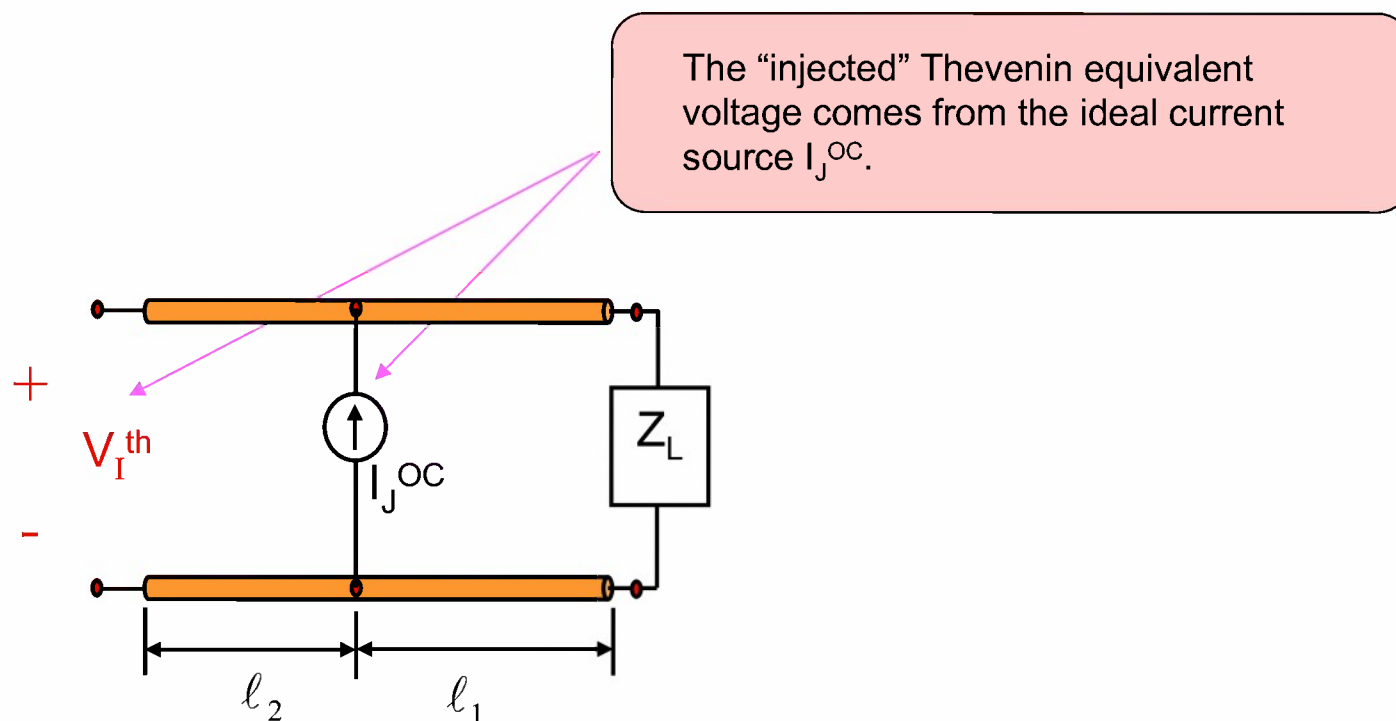
# Separation of the Two Mechanisms

Two ideal current sources are added at the junction



Two ideal current sources

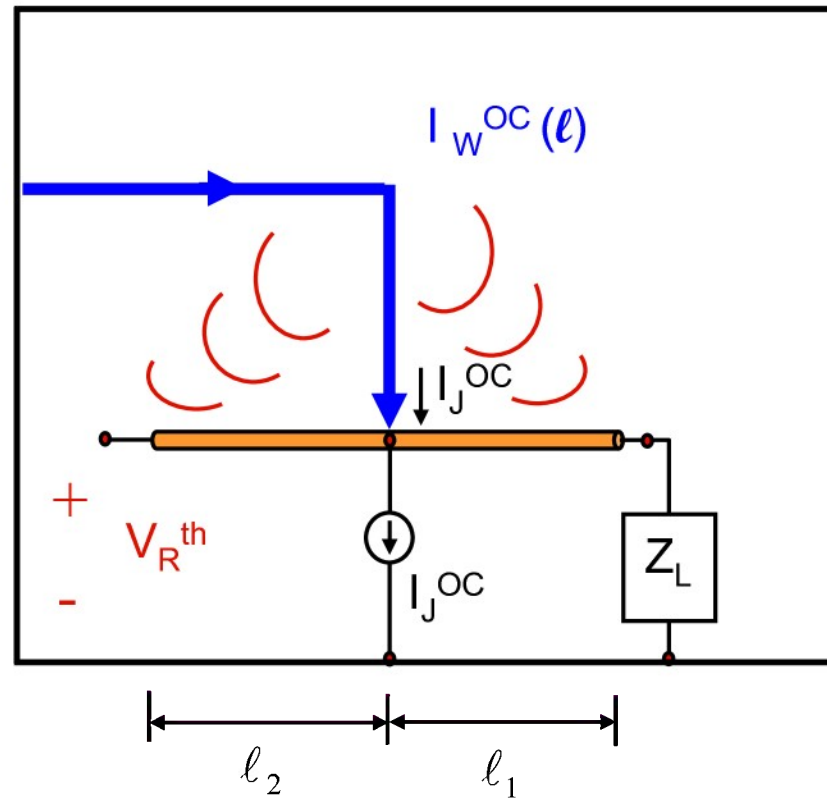
# Mechanism 1: Injection Current



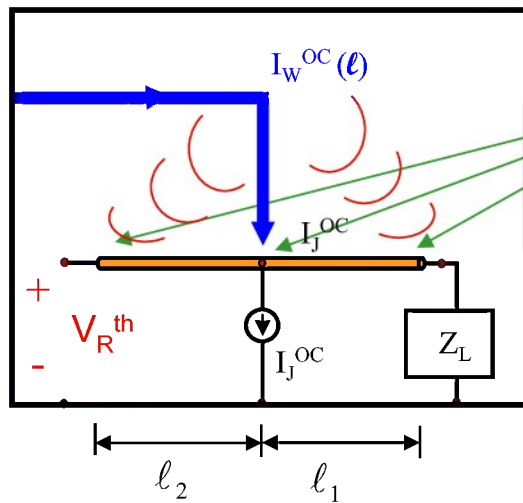
Simple transmission line theory is used to calculate  $V_I^{th}$

## Mechanism 2: Radiation From Feed Wire

Radiation from feed wire creates a distributed voltage source along the PCB wire



## Mechanism 2 (cont.)

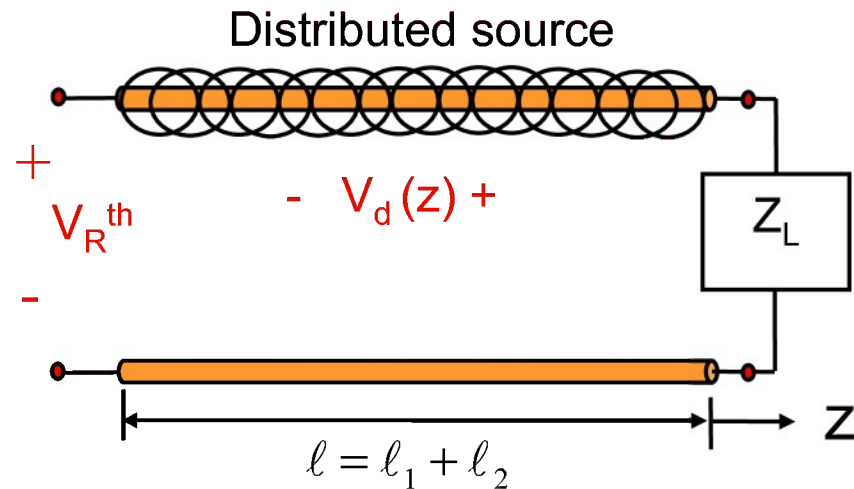


Use EIGER to calculate the impressed electric field on the PCB wire (in the presence of the cavity)

$$\mathbf{E}^{imp}(z) = -j\omega \mathbf{A} - \nabla \Phi$$

Calculation of potential ignores point charge at the end of the terminated feed current

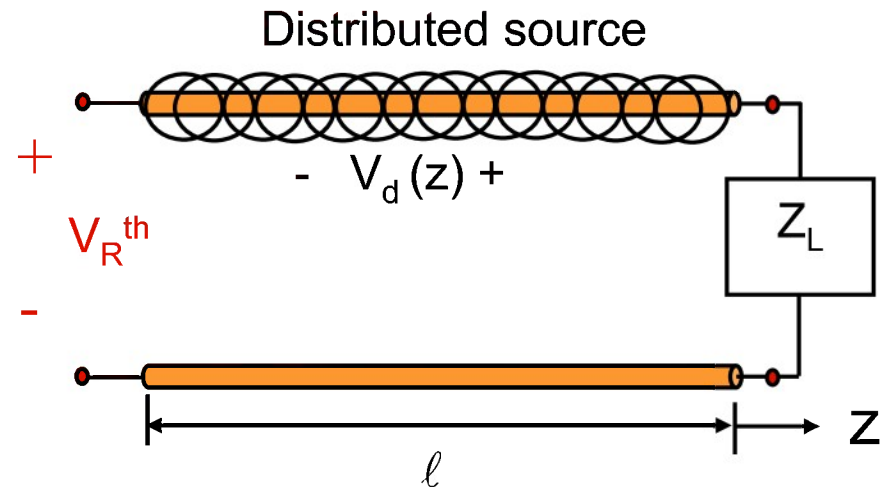
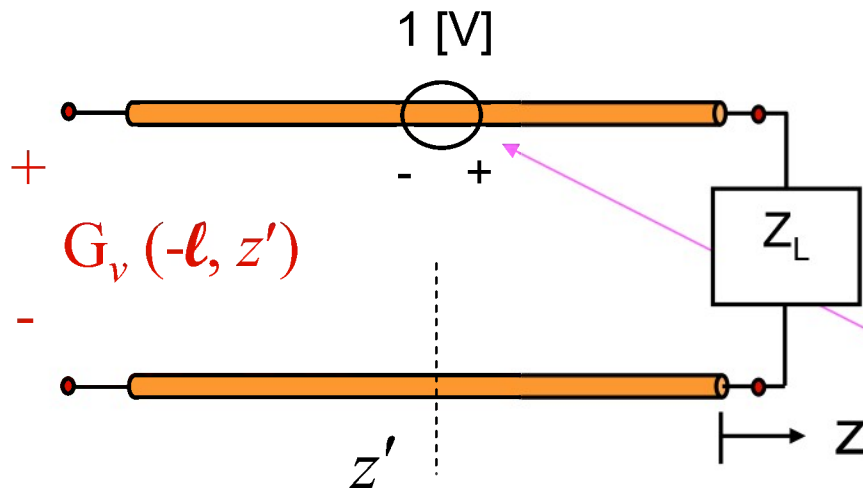
$$V_d(z) = E^{imp}(z)$$



## Mechanism 2 (cont.)

The Thevenin equivalent voltage,  $V_R^{th}$ , can be calculated by integrating over the TL Green's function:

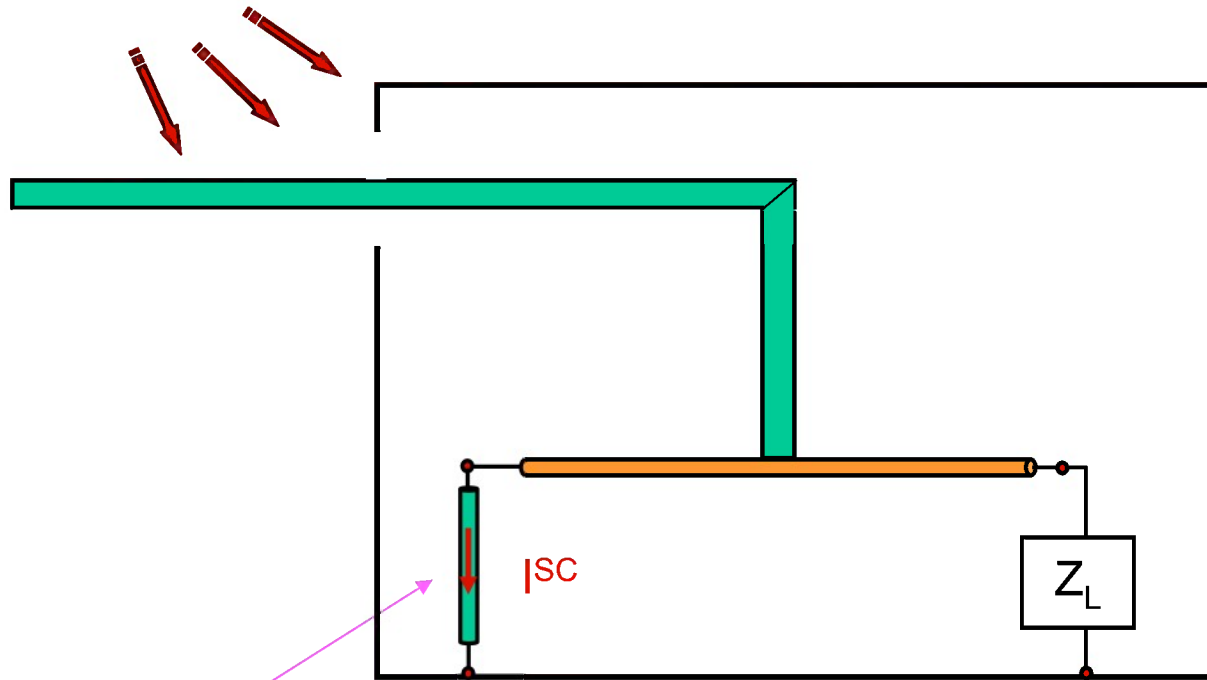
$$V_R^{th} = \int_{-\ell}^0 V_d(z') G_v(-\ell, z') dz'$$



A unit voltage source on the transmission line defines the Green's function.



# Calculation of Short Circuit Current, $I^{SC}$

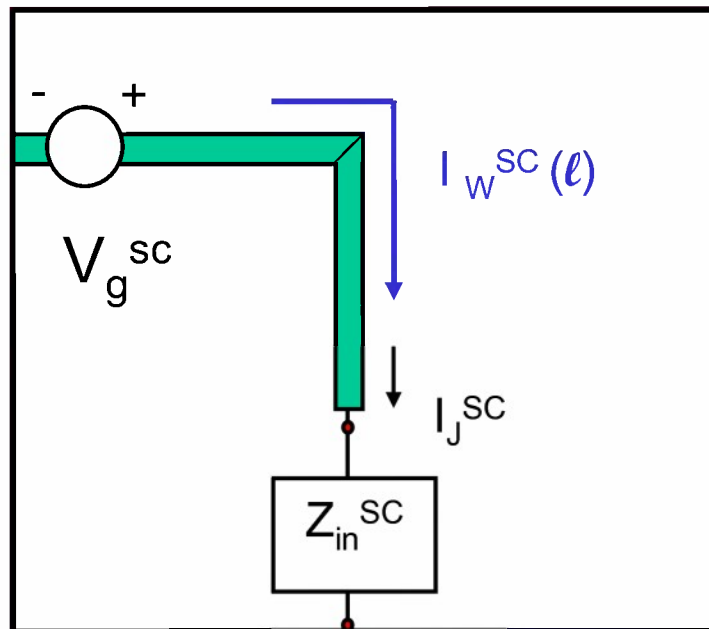


short circuit current at the Thevenin port

## Short Circuit Current, $I^{SC}$ (cont.)

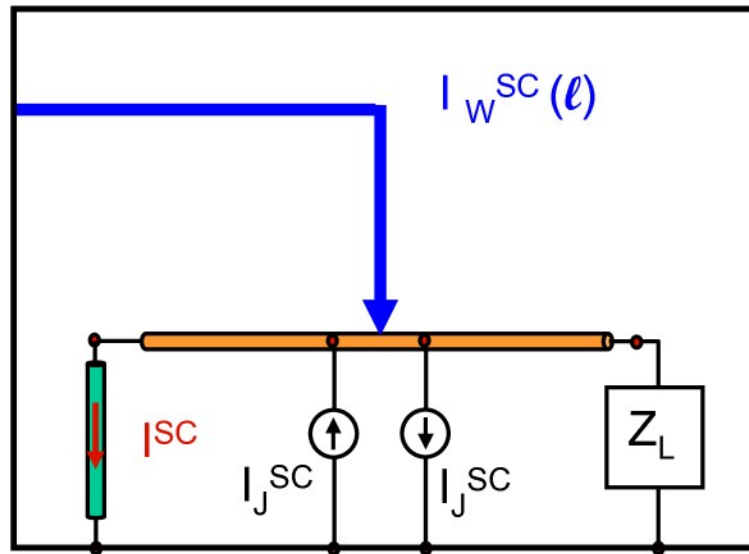
Procedure is similar to that used to obtain Thevenin (open-circuit) voltage:

Different terminating impedance results in a different gap voltage source



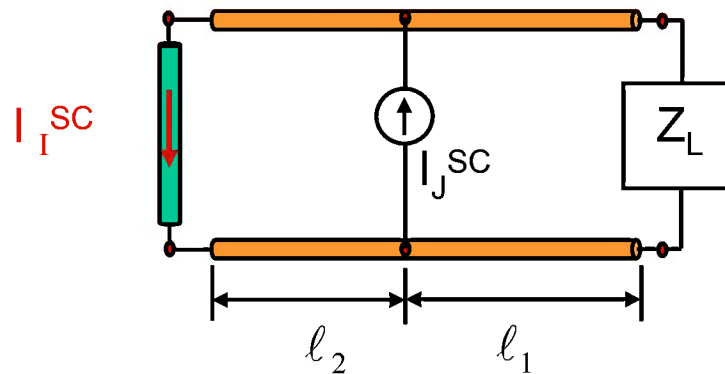
## Short Circuit Current, $I^{SC}$ (cont.)

Equivalence principle is used, and two ideal current sources are added, as before.



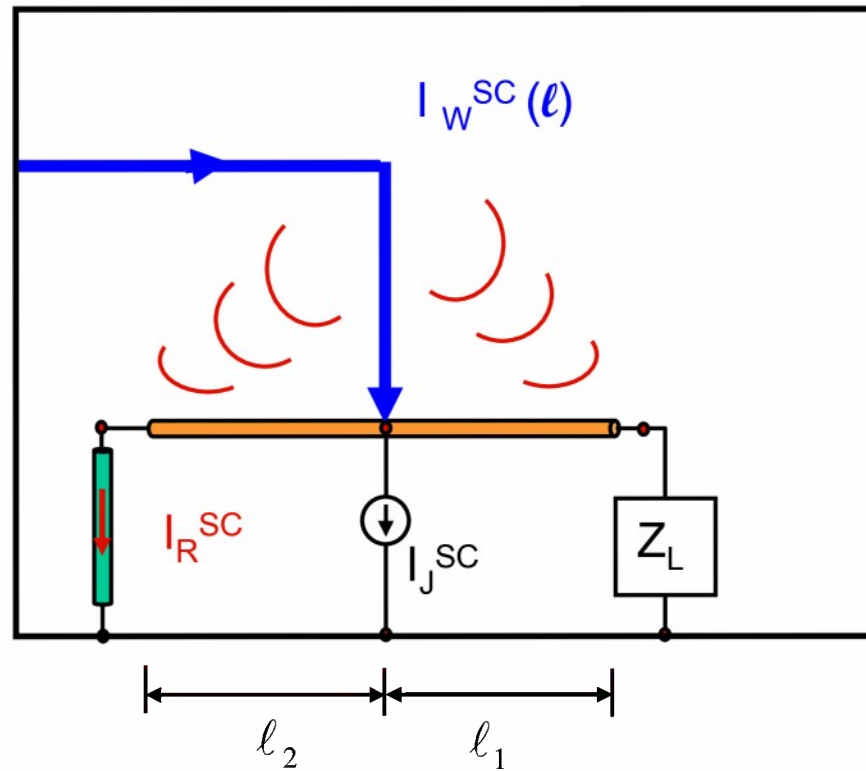
$$I^{SC} = I_I^{SC} + I_R^{SC}$$

## Mechanism 1: Injection Current

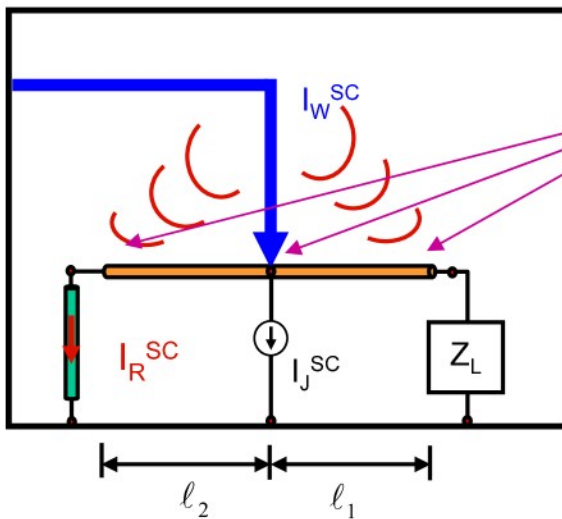


Transmission line theory is used to find the short-circuit current due to the injected source.

## Mechanism 2: Radiation From Feed Wire



## Mechanism 2 (cont.)

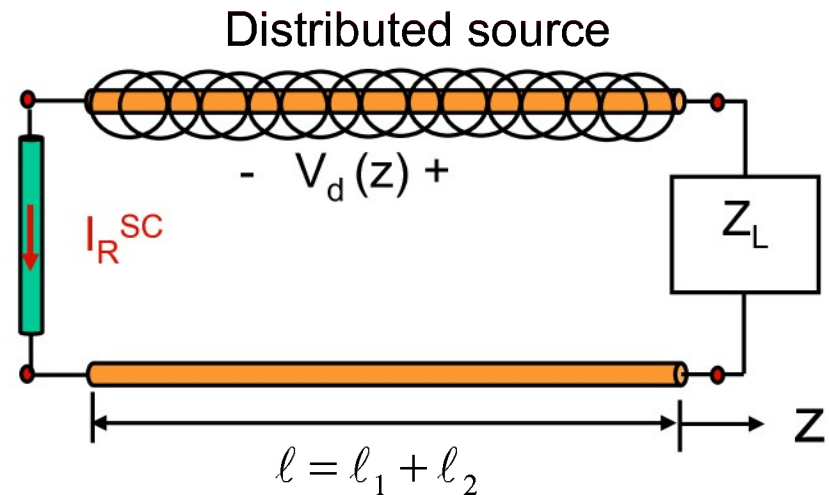


Use EIGER to calculate impressed field on the PCB wire.

$$V_d(z) = E^{imp}(z)$$

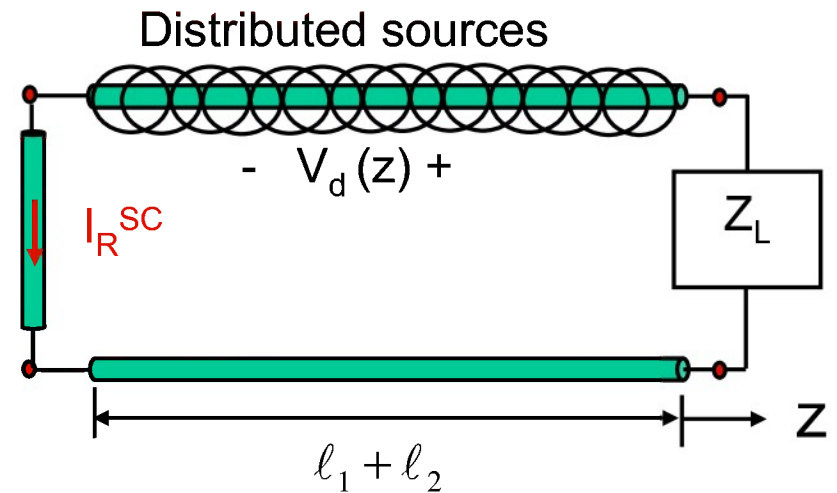
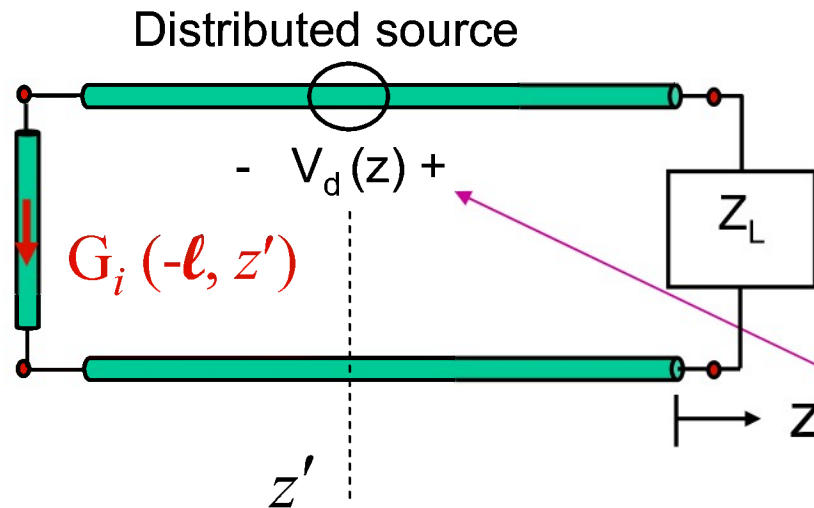
$$E^{imp}(z) = -j\omega A - \nabla\Phi$$

Calculation of potential ignores point charge at the end of the terminated feed current



## Mechanism 2 (cont.)

$$I_R^{sc} = \int_{-\ell}^0 V_d(z') G_i(-\ell, z') dz'$$



An unit voltage source on the transmission line defines the Green's function.

# Future Work

- Obtain numerical results using EIGER for example problem
- Validate approach by “brute force” comparison